

Retail Auto ID Experts Speak Out in Chicago

The AIM Expo, Nov. 1-3 in Chicago, IL has engaged the leading industry experts and end-users for a complete showcase of auto ID & mobile IT solutions for **retail**. Learn how you, too, can take advantage of auto ID & mobile IT technologies to reduce costs by improving traceability, accuracy, loss prevention and customer fulfillment.

Hear from the following distinguished faculty members, among others:



Paula Giovannetti
Foundation Data Planner,
Best Buy Company, Inc.



Bill Hardgrave
Dean, Business School,
Auburn University



Nikki Baird
Managing Partner
Retail Systems
Research



Simon Ellis
Supply Chain Strategies,
IDC Manufacturing
Insights

Who Should Attend?

- Application/Systems/Packaging Engineers
- Asset/Facility/Plant/Property Managers
- Brand Managers
- Financial Management/Analysts
- Retail Operations
- Senior Executives
- Supply Chain Management
- Warehouse/Distribution/Logistics Management



Vertical Market Education – in-depth look at government, healthcare, retail and manufacturing case studies that share the latest information about solutions that are delivering real results.

General Sessions – providing practical insight on critical considerations to enhance your business processes.

Solutions Showcase – see and touch solutions to streamline processes, achieve successful implementations, and maintain expected levels of compliance

Networking – no event would be complete without connecting partners, customers, and industry experts – AIM is noted for its networking value!

Make plans now to join AIM in Chicago • www.AIM-Expo.com

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